

DDR3 SDRAM

SUM512M8 – 64 Meg x 8 x 8 Banks

SUU512M8 – 64 Meg x 8 x 8 Banks

SUM256M16 – 32 Meg x 16 x 8 Banks

SUU256M16 – 32 Meg x 16 x 8 Bank

Features

- $V_{DD} = V_{DDQ} = +1.35V$ (1.283V–1.45V)
- Backward compatible to $V_{DD} = V_{DDQ} = 1.35V \pm 0.075V$
 - Supports DDR3L devices to be backward compatible in 1.5V applications
- Differential bidirectional data strobe
- 8n-bit prefetch architecture
- Differential clock inputs (CK, CK#)
- 8 internal banks
- Nominal and dynamic on-die termination (ODT) for data, strobe, and mask signals
- Programmable CAS (READ) latency (CL)
- Posted CAS Addictive latency (AL)
- Programmable CAS (WRITE) latency (CWL) based on t_{CK}
- Fixed burst length (BL) of 8 and burst chop (BC) of 4 (via the mode register set [MRS])
- Selectable BC4 or BL8 on-the-fly (OTF)
- Self refresh mode
- T_C of 0°C to 95°C
 - 64ms, 8,192 cycle refresh at 0°C to 85°C
 - 32ms, 8,192 cycle refresh at 85°C to 95°C
- Self refresh temperature (SRT)
- Write leveling
- Multipurpose register
- Output driver calibration

Options

- Configuration
 - 1 Gig x 4
 - 512 Meg x 8
 - 256 Meg x 16
- FBGA package (Pb-free) - x4, x8
 - 78-ball (10.5mm x 12mm) Rev. D
 - 78-ball (9mm x 10.5mm) Rev. E, J
 - 78-ball (7.5mm x 10.6mm) Rev. N
- FBGA package (Pb-free) - x16
 - 96-ball (10mm x 14mm) Rev. D
 - 96-ball (9mm x 14mm) Rev. E
 - 96-ball (9mm x 14mm) Rev. N
- Timing - cycle time
 - 938ps @ CL = 14 (DDR3-2133)
 - 1.071ns @ CL = 13 (DDR3-1866)
 - 1.25ns @ CL = 11 (DDR3-1600)
 - 1.5ns @ CL = 9 (DDR3-1333)
 - 1.87ns @ CL = 7 (DDR3-1066)
- Operating temperature
 - Commercial (0°C ≤ T_C 95°C ≤ T_C)
- Revision

Marking

1G4
 512M8
 256M16

RAF
 RHF
 RGF

REF
 HAF
 LYF

-093
 -107
 -125
 -15E
 -187E

:D/:E/:J/:N

- Note: 1. Note all options listed can be combined to define an offered product. Use the part catalog search on <http://www.micron.com> for available offerings.
2. Contact SpecTek Sales for details on availability of the "X" placeholders and product availability.

Table 1: Key Timing Parameters

Speed Grade	Data Rate (MT/s)	Target ^t RCD- ^t RP-CL	^t RCD (ns)	^t RP (ns)	CL (ns)
-093 ^{1,2,3,4}	2133	14-14-14	13.09	13.09	13.09
-107 ^{1,2,3}	1866	13-13-13	13.91	13.91	13.91
-125 ^{1,2}	1600	11-11-11	13.75	13.75	13.75
-15E ¹	1333	9-9-9	13.5	13.5	13.5
-187E	1066	7-7-7	13.1	13.1	13.1

- Notes: 1. Backward compatible to 1066, CL = 7 (-187E).
 2. Backward compatible to 1333, CL = 9 (-15E).
 3. Backward compatible to 1600, CL = 11 (-125).
 4. Backward compatible to 1066, CL = 13 (-107).

Table 2: Addressing

Parameter	1 Gig x 4	512 Meg x 8	256 Meg x 16
Configuration	128 Meg x 4 x 8 banks	64 Meg x 8 x 8 banks	32 Meg x 16 x 8 banks
Refresh count	8K	8K	8K
Row addressing	64K (A[15:0])	64K (A[15:0])	32K (A[14:0])
Bank addressing	8 (BA[2:0])	8 (BA[2:0])	8 (BA[2:0])
Column addressing	2K (A[11, 9:0])	1K (A[9:0])	1K (A[9:0])
Page size	1KB	1KB	2KB

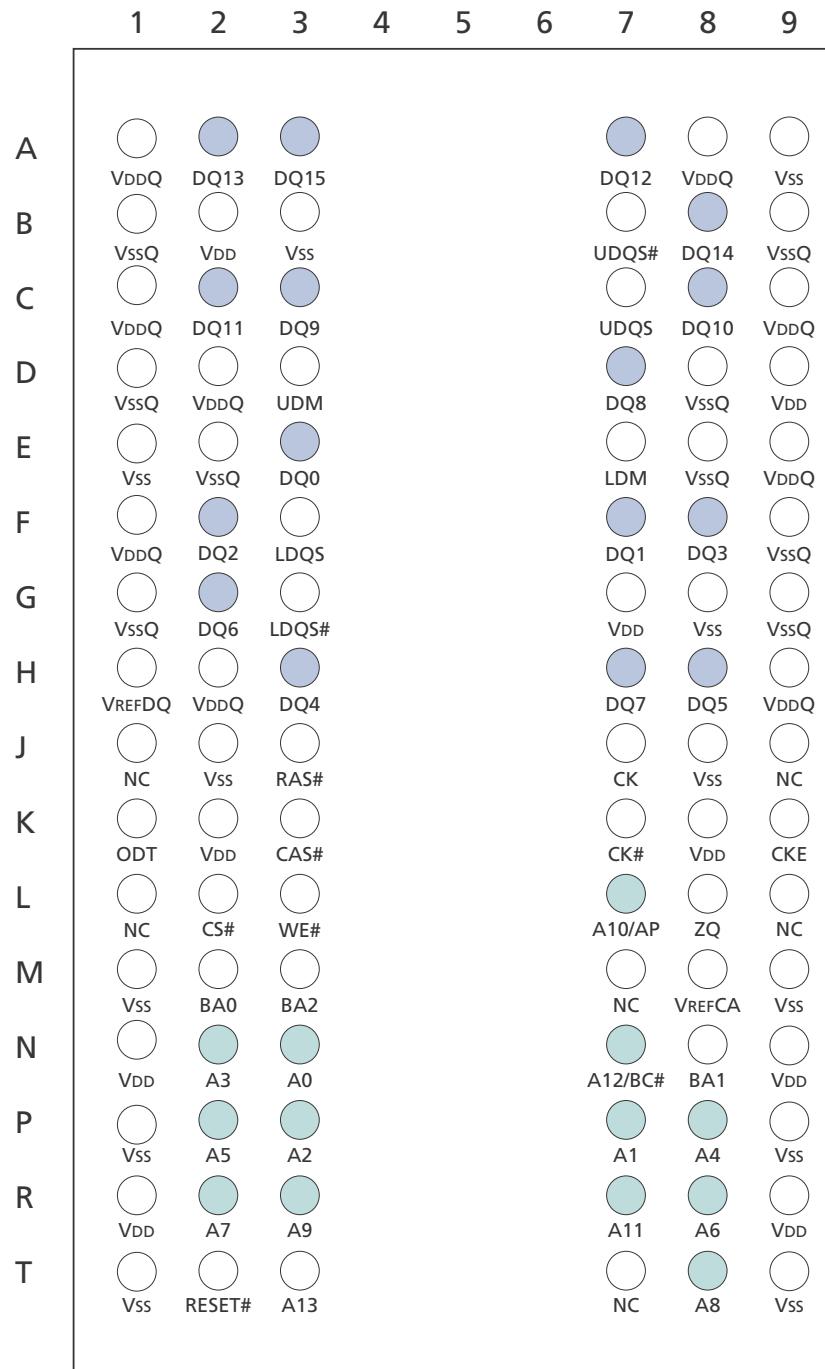
Ball Assignments and Descriptions

Figure 1: 78-Ball FBGA – x4, x8 Ball Assignments (Top View)

	1	2	3	4	5	6	7	8	9
A	V _{SS}	V _{DD}	NC				NF, NF/TDQS#	V _{SS}	V _{DD}
B	V _{SS}	V _{SS} Q	DQ0				DM, DM/TDQS	V _{SS} Q	V _{DD} Q
C	V _{DD} Q	DQ2	DQS				DQ1	DQ3	V _{SS} Q
D	V _{SS} Q	NF, DQ6	DQS#				V _{DD}	V _{SS}	V _{SS} Q
E	V _{REF} DQ	V _{DD} Q	NF, DQ4				NF, DQ7	NF, DQ5	V _{DD} Q
F	NC	V _{SS}	RAS#				CK	V _{SS}	NC
G	ODT	V _{DD}	CAS#				CK#	V _{DD}	CKE
H	NC	CS#	WE#				A10/AP	ZQ	NC
J	V _{SS}	BA0	BA2				NC	V _{REF} CA	V _{SS}
K	V _{DD}	A3	A0				A12/BC#	BA1	V _{DD}
L	V _{SS}	A5	A2				A1	A4	V _{SS}
M	V _{DD}	A7	A9				A11	A6	V _{DD}
N	V _{SS}	RESET#	A13				A14	A8	V _{SS}

- Notes: 1. Ball descriptions listed in Table 3 on page 5 are listed as “x4, x8” if unique; otherwise, x4 and x8 are the same.
2. A comma separates the configuration; a slash defines a selectable function.
Example D7 = NF, NF/TDQS#. NF applies to the x4 configuration only. NF/TDQS# applies to the x8 configuration only—selectable between NF or TDQS# via MRS (symbols are defined in Table 3 on page 5).

Figure 2: 96-Ball FBGA – x16 Ball Assignments (Top View)



- Notes:
- Ball descriptions listed in Table 4 on page 7 are listed as “x4, x8” if unique; otherwise, x4 and x8 are the same.
 - A comma separates the configuration; a slash defines a selectable function.
Example D7 = NF, NF/TDQS#. NF applies to the x4 configuration only. NF/TDQS# applies to the x8 configuration only—selectable between NF or TDQS# via MRS (symbols are defined in Table 4 on page 7).

Table 3: 78-Ball FBGA – x4, x8 Ball Descriptions

Symbol	Type	Description
A0, A1, A2, A3, A4, A5, A6, A7, A8, A9, A10/AP, A11, A12/BC#, A13, A14, A15	Input	Address inputs: Provide the row address for ACTIVATE commands, and the column address and auto precharge bit (A10) for READ/WRITE commands, to select one location out of the memory array in the respective bank. A10 sampled during a PRECHARGE command determines whether the PRECHARGE applies to one bank (A10 LOW, bank selected by BA[2:0]) or all banks (A10 HIGH). The address inputs also provide the op-code during a LOAD MODE command. Address inputs are referenced to V_{REFCA} . A12/BC#: When enabled in the mode register (MR), A12 is sampled during READ and WRITE commands to determine whether burst chop (on-the-fly) will be performed (HIGH = BL8 or no burst chop, LOW = BC4).
BA0, BA1, BA2	Input	Bank address inputs: BA[2:0] define the bank to which an ACTIVATE, READ, WRITE, or PRECHARGE command is being applied. BA[2:0] define which mode register (MR0, MR1, MR2, or MR3) is loaded during the LOAD MODE command. BA[2:0] are referenced to V_{REFCA} .
CK, CK#	Input	Clock: CK and CK# are differential clock inputs. All control and address input signals are sampled on the crossing of the positive edge of CK and the negative edge of CK#. Output data strobe (DQS, DQS#) is referenced to the crossings of CK and CK#.
CKE	Input	Clock enable: CKE enables (registered HIGH) and disables (registered LOW) internal circuitry and clocks on the DRAM. The specific circuitry that is enabled/disabled is dependent upon the DDR3 SDRAM configuration and operating mode. Taking CKE LOW provides PRECHARGE POWER-DOWN and SELF REFRESH operations (all banks idle), or active power-down (row active in any bank). CKE is synchronous for power-down entry and exit and for self refresh entry. CKE is asynchronous for self refresh exit. Input buffers (excluding CK, CK#, CKE, RESET#, and ODT) are disabled during POWER-DOWN. Input buffers (excluding CKE and RESET#) are disabled during SELF REFRESH. CKE is referenced to V_{REFCA} .
CS#	Input	Chip select: CS# enables (registered LOW) and disables (registered HIGH) the command decoder. All commands are masked when CS# is registered HIGH. CS# provides for external rank selection on systems with multiple ranks. CS# is considered part of the command code. CS# is referenced to V_{REFCA} .
DM	Input	Input data mask: DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH along with the input data during a write access. Although the DM ball is input-only, the DM loading is designed to match that of the DQ and DQS balls. DM is referenced to V_{REFDQ} . DM has an optional use as TDQS on the x8.
ODT	Input	On-die termination: ODT enables (registered HIGH) and disables (registered LOW) termination resistance internal to the DDR3 SDRAM. When enabled in normal operation, ODT is only applied to each of the following balls: DQ[7:0], DQS, DQS#, and DM for the x8; DQ[3:0], DQS, DQS#, and DM for the x4. The ODT input is ignored if disabled via the LOAD MODE command. ODT is referenced to V_{REFCA} .
RAS#, CAS#, WE#	Input	Command inputs: RAS#, CAS#, and WE# (along with CS#) define the command being entered and are referenced to V_{REFCA} .
RESET#	Input	Reset: RESET# is an active LOW CMOS input referenced to V_{SS} . The RESET# input receiver is a CMOS input defined as a rail-to-rail signal with DC HIGH $\geq 0.8 \times V_{DD}$ and DC LOW $\leq 0.2 \times V_{DDQ}$. RESET# assertion and desertion are asynchronous.
DQ0, DQ1, DQ2, DQ3	I/O	Data input/output: Bidirectional data bus for the x4 configuration. DQ[3:0] are referenced to V_{REFDQ} .
DQ0, DQ1, DQ2, DQ3, DQ4, DQ5, DQ6, DQ7	I/O	Data input/output: Bidirectional data bus for the x8 configuration. DQ[7:0] are referenced to V_{REFDQ} .
DQS, DQS#	I/O	Data strobe: Output with read data. Edge-aligned with read data. Input with write data. Center-aligned to write data.
TDQS, TDQS#	Output	Termination data strobe: Applies to the x8 configuration only. When TDQS is enabled, DM is disabled, and the TDQS and TDQS# balls provide termination resistance.

Table 3: 78-Ball FBGA – x4, x8 Ball Descriptions (Continued)

Symbol	Type	Description
V_{DD}	Supply	Power supply: 1.35V (1.283–1.45V) / 1.5V \pm 0.075V (backward compatible).
V_{DDQ}	Supply	DQ power supply: 1.35V (1.283–1.45V) / 1.5V \pm 0.075V (backward compatible). Isolated on the device for improved noise immunity.
V_{REFA}	Supply	Reference voltage for control, command, and address: V_{REFA} must be maintained at all times (including self refresh) for proper device operation.
V_{REFDQ}	Supply	Reference voltage for data: V_{REFDQ} must be maintained at all times (excluding self refresh) for proper device operation.
V_{SS}	Supply	Ground.
V_{SSQ}	Supply	DQ ground: Isolated on the device for improved noise immunity.
ZQ	Reference	External reference ball for output drive calibration: This ball is tied to an external 240 Ω resistor (RZQ), which is tied to V_{SSQ} .
NC	–	No connect: These balls should be left unconnected (the ball has no connection to the DRAM or to other balls).
NF	–	No function: When configured as a x4 device, these balls are NF. When configured as a x8 device, these balls are defined as TDQS#, DQ[7:4].

Table 4: 96-Ball FBGA – x16 Ball Descriptions

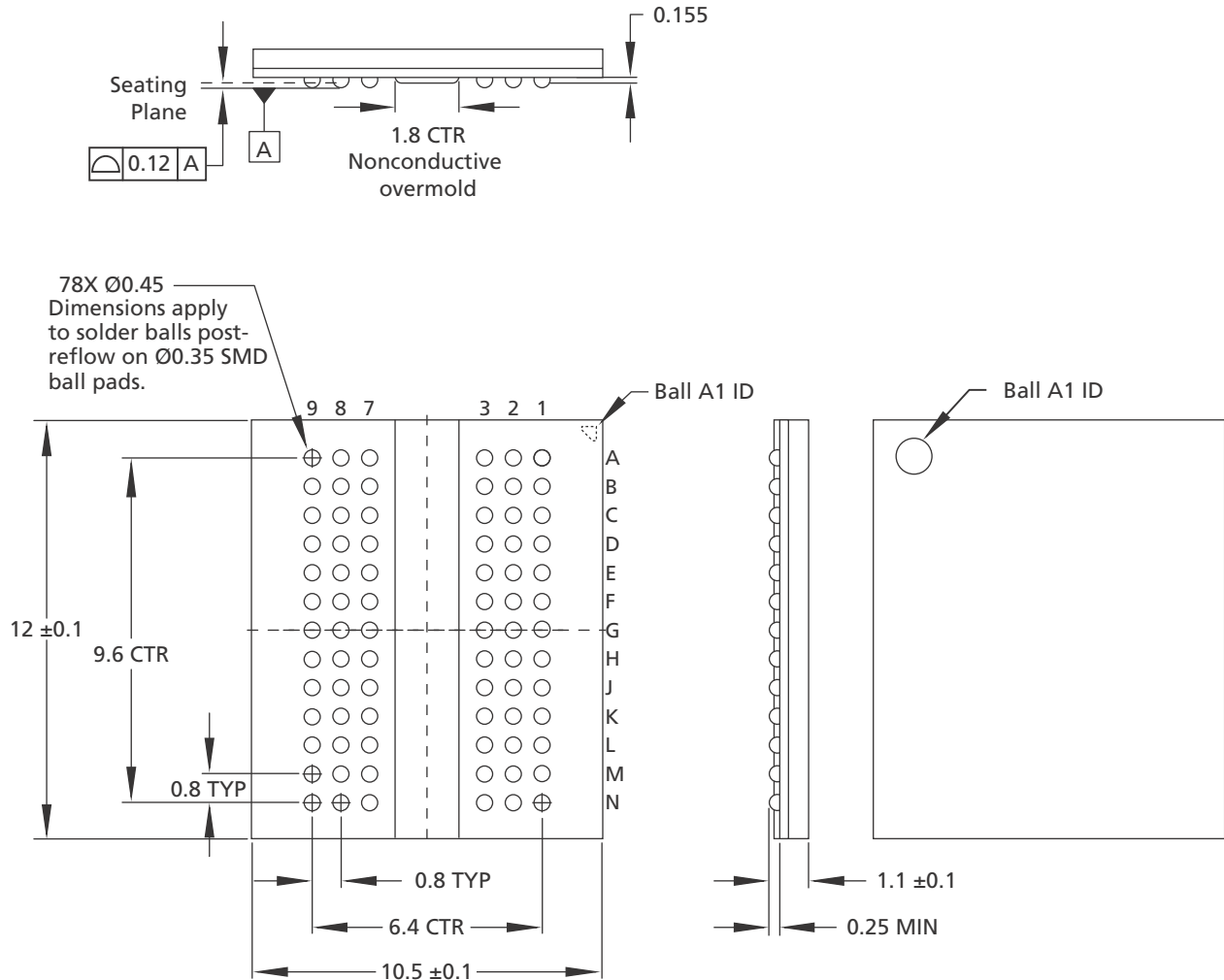
Symbol	Type	Description
A0, A1, A2, A3, A4, A5, A6, A7, A8, A9, A10/AP, A11, A12/BC#, A13, A14, A15	Input	Address inputs: Provide the row address for ACTIVATE commands, and the column address and auto precharge bit (A10) for READ/WRITE commands, to select one location out of the memory array in the respective bank. A10 sampled during a PRECHARGE command determines whether the PRECHARGE applies to one bank (A10 LOW, bank selected by BA[2:0]) or all banks (A10 HIGH). The address inputs also provide the op-code during a LOAD MODE command. Address inputs are referenced to V_{REFCA} . A12/BC#: When enabled in the mode register (MR), A12 is sampled during READ and WRITE commands to determine whether burst chop (on-the-fly) will be performed (HIGH = BL8 or no burst chop, LOW = BC4).
BA0, BA1, BA2	Input	Bank address inputs: BA[2:0] define the bank to which an ACTIVATE, READ, WRITE, or PRECHARGE command is being applied. BA[2:0] define which mode register (MR0, MR1, MR2, or MR3) is loaded during the LOAD MODE command. BA[2:0] are referenced to V_{REFCA} .
CK, CK#	Input	Clock: CK and CK# are differential clock inputs. All control and address input signals are sampled on the crossing of the positive edge of CK and the negative edge of CK#. Output data strobe (DQS, DQS#) is referenced to the crossings of CK and CK#.
CKE	Input	Clock enable: CKE enables (registered HIGH) and disables (registered LOW) internal circuitry and clocks on the DRAM. The specific circuitry that is enabled/disabled is dependent upon the DDR3 SDRAM configuration and operating mode. Taking CKE LOW provides PRECHARGE POWER-DOWN and SELF REFRESH operations (all banks idle), or active power-down (row active in any bank). CKE is synchronous for power-down entry and exit and for self refresh entry. CKE is asynchronous for self refresh exit. Input buffers (excluding CK, CK#, CKE, RESET#, and ODT) are disabled during POWER-DOWN. Input buffers (excluding CKE and RESET#) are disabled during SELF REFRESH. CKE is referenced to V_{REFCA} .
CS#	Input	Chip select: CS# enables (registered LOW) and disables (registered HIGH) the command decoder. All commands are masked when CS# is registered HIGH. CS# provides for external rank selection on systems with multiple ranks. CS# is considered part of the command code. CS# is referenced to V_{REFCA} .
LDM	Input	Input data mask: LDM is a lower-byte, input mask signal for write data. Lower-byte input data is masked when LDM is sampled HIGH along with the input data during a write access. Although the LDM ball is input-only, the LDM loading is designed to match that of the DQ and DQS balls. LDM is referenced to V_{REFDQ} .
ODT	Input	On-die termination: ODT enables (registered HIGH) and disables (registered LOW) termination resistance internal to the DDR3 SDRAM. When enabled in normal operation, ODT is only applied to each of the following balls: DQ[15:0], LDQS, LDQS#, UDQS, UDQS#, LDM, and UDM for the x16; DQ0[7:0], DQS, DQS#, DM/TDQS, and NF/TDQS# (when TDQS is enabled) for the x8; DQ[3:0], DQS, DQS#, and DM for the x4. The ODT input is ignored if disabled via the LOAD MODE command. ODT is referenced to V_{REFCA} .
RAS#, CAS#, WE#	Input	Command inputs: RAS#, CAS#, and WE# (along with CS#) define the command being entered and are referenced to V_{REFCA} .
RESET#	Input	Reset: RESET# is an active LOW CMOS input referenced to V_{SS} . The RESET# input receiver is a CMOS input defined as a rail-to-rail signal with DC HIGH $\geq 0.8 \times V_{DD}$ and DC LOW $\leq 0.2 \times V_{DDQ}$. RESET# assertion and desertion are asynchronous.
UDM	Input	Input data mask: UDM is an upper-byte, input mask signal for write data. Upper-byte input data is masked when UDM is sampled HIGH along with that input data during a WRITE access. Although the UDM ball is input-only, the UDM loading is designed to match that of the DQ and DQS balls. UDM is referenced to V_{REFDQ} .
DQ0, DQ1, DQ2, DQ3, DQ4, DQ5, DQ6, DQ7	I/O	Data input/output: Lower byte of bidirectional data bus for the x16 configuration. DQ[7:0] are referenced to V_{REFDQ} .

Table 4: 96-Ball FBGA – x16 Ball Descriptions (Continued)

Symbol	Type	Description
DQ8, DQ9, DQ10, DQ11, DQ12, DQ13, DQ14, DQ15	I/O	Data input/output: Upper byte of bidirectional data bus for the x16 configuration. DQ[15:8] are referenced to V_{REFDQ} .
LDQS, LDQS#	I/O	Lower byte data strobe: Output with read data. Edge-aligned with read data. Input with write data. Center-aligned to write data.
UDQS, UDQS#	I/O	Upper byte data strobe: Output with read data. Edge-aligned with read data. Input with write data. DQS is center-aligned to write data.
V_{DD}	Supply	Power supply: 1.5V \pm 0.075V.
V_{DDQ}	Supply	DQ power supply: 1.5V \pm 0.075V. Isolated on the device for improved noise immunity.
V_{REFCA}	Supply	Reference voltage for control, command, and address: V_{REFCA} must be maintained at all times (including self refresh) for proper device operation.
V_{REFDQ}	Supply	Reference voltage for data: V_{REFDQ} must be maintained at all times (excluding self refresh) for proper device operation.
V_{SS}	Supply	Ground.
V_{SSQ}	Supply	DQ ground: Isolated on the device for improved noise immunity.
ZQ	Reference	External reference ball for output drive calibration: This ball is tied to an external 240 Ω resistor (RZQ), which is tied to V_{SSQ} .
NC	-	No connect: These balls should be left unconnected (the ball has no connection to the DRAM or to other balls).

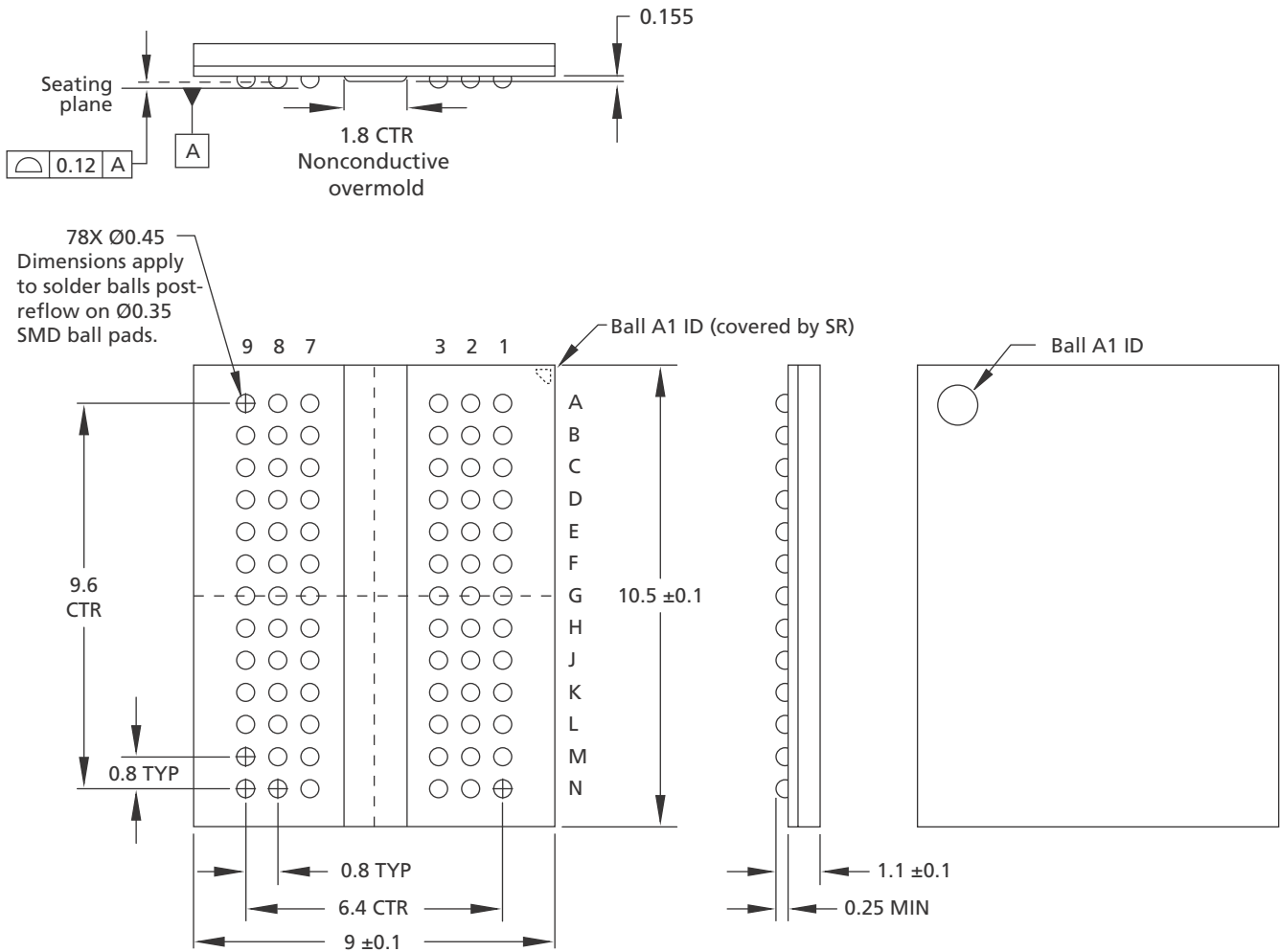
Package Dimensions

Figure 3: 78-Ball FBGA – x4, x8; “RAF”



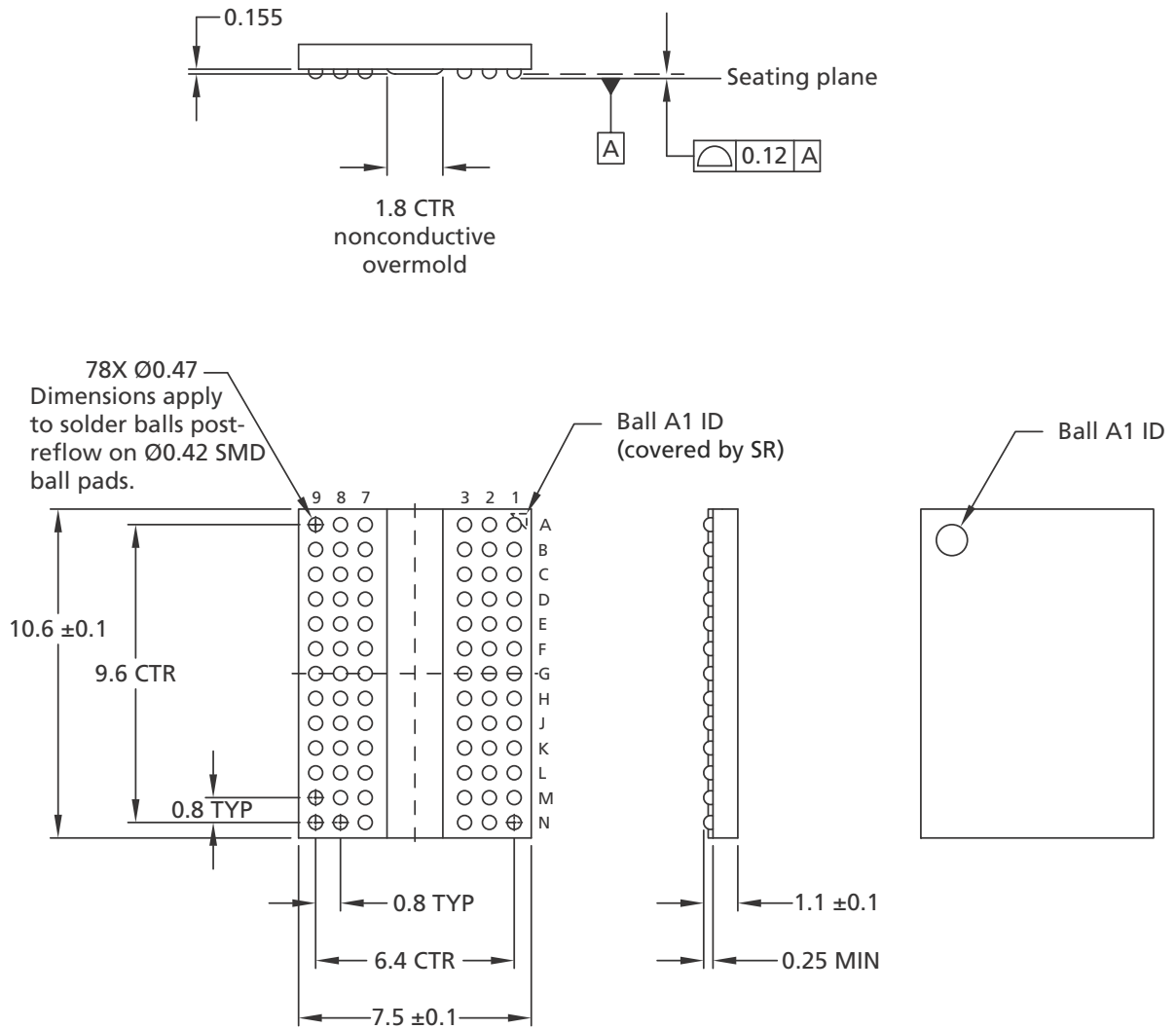
- Notes: 1. All dimensions are in millimeters.
2. Solder ball material: SAC305 (96.5% Sn, 3% Ag, 0.5% Cu)

Figure 4: 78-Ball FBGA – x4, x8; “RHF”



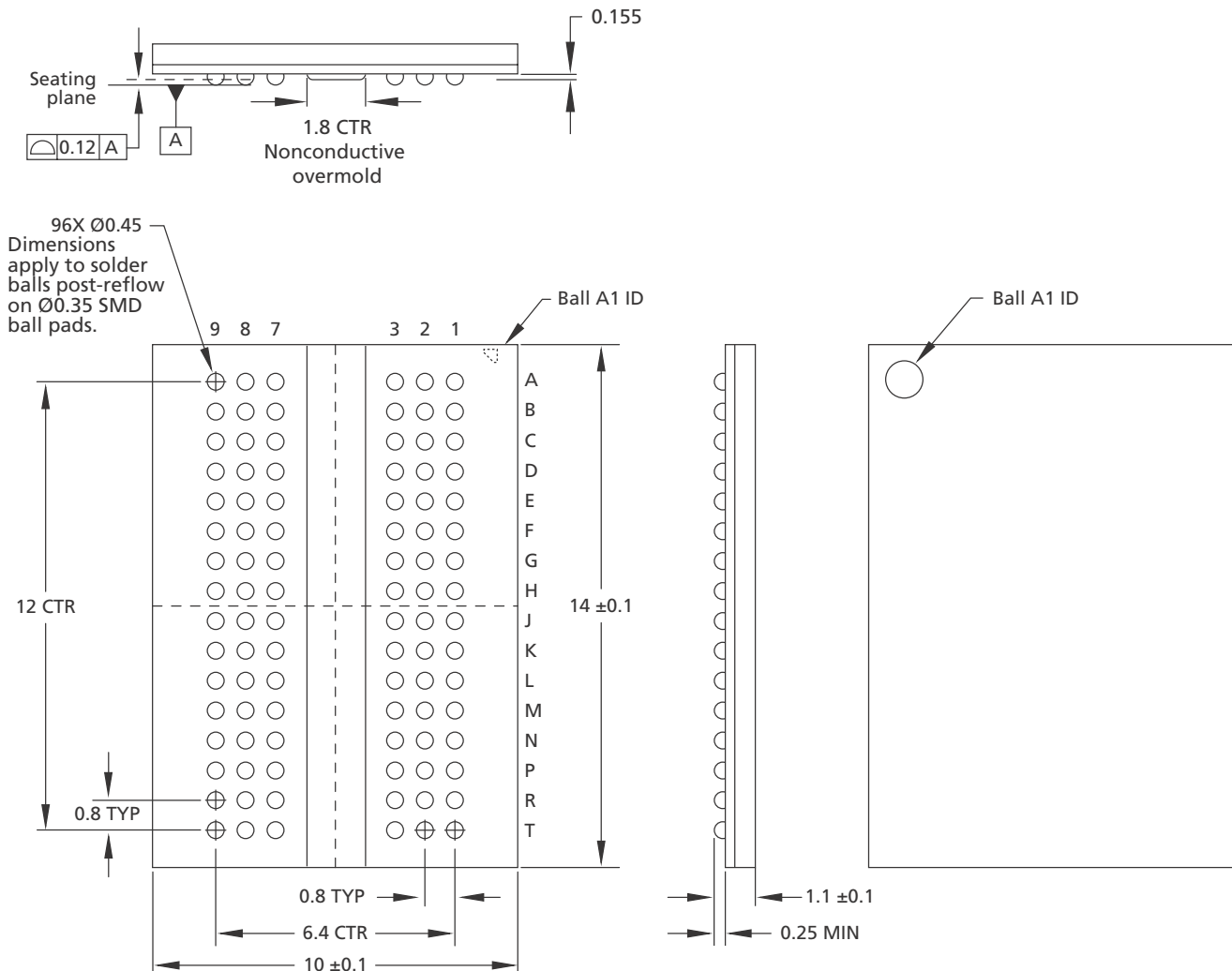
- Notes: 1. All dimensions are in millimeters.
 2. Solder ball material: SAC305 (96.5% Sn, 3% Ag, 0.5% Cu)

Figure 5: 78-Ball FBGA – x4, x8; “RGF”



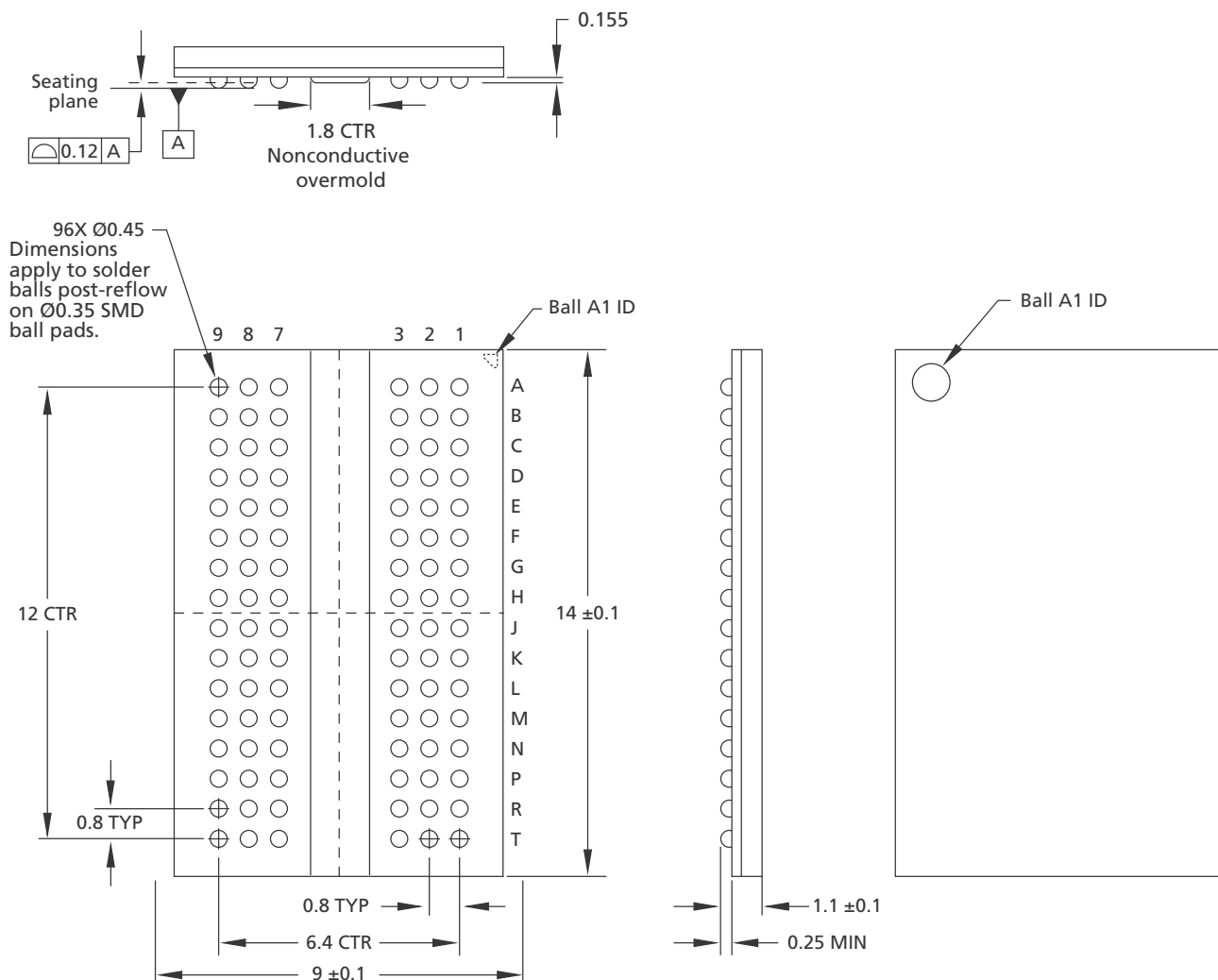
- Notes: 1. All dimensions are in millimeters.
2. Solder ball material: SAC305 (96.5% Sn, 3% Ag, 0.5% Cu)

Figure 6: 96-Ball FBGA - x16; "REF"



- Notes: 1. All dimensions are in millimeters.
2. Solder ball material: SAC305 (96.5% Sn, 3% Ag, 0.5% Cu)

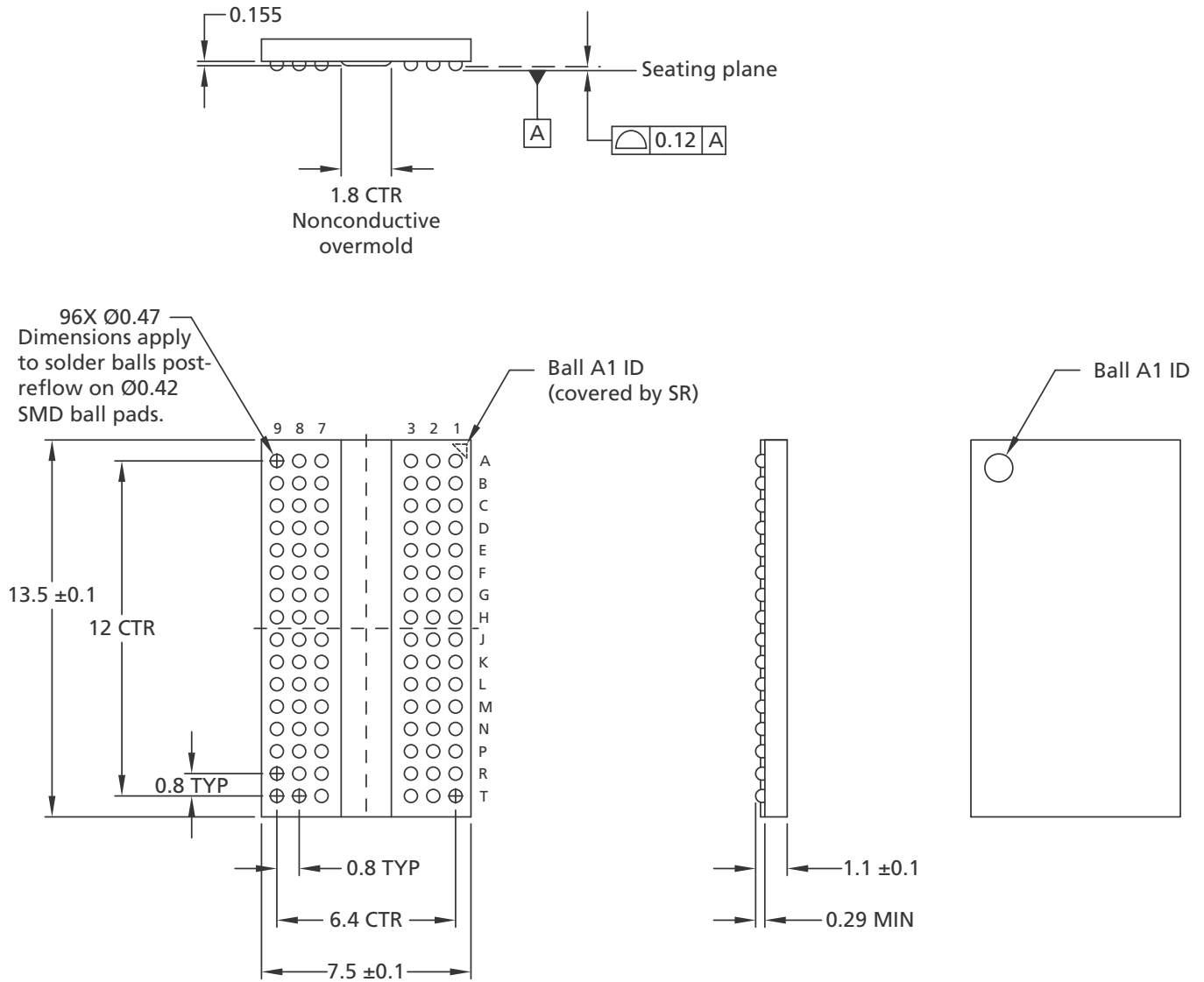
Figure 7: 96-Ball FBGA - x16; "HAF"



- Notes: 1. All dimensions are in millimeters.
2. Solder ball material: SAC305 (96.5% Sn, 3% Ag, 0.5% Cu)

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Figure 8: 96-Ball FBGA - x16; "LYF"



- Notes: 1. All dimensions are in millimeters.
2. Solder ball material: SAC305 (96.5% Sn, 3% Ag, 0.5% Cu)